

## Three level inverter Power Module

Trench & Field Stop IGBT3 Q2, Q3:  $V_{CES} = 600V$ ;  $I_C = 50A$  @  $T_C = 80$ °C

Super junction MOSFET Q1, Q4:

 $V_{DSS} = 600V$ ;  $I_D = 29A$  @  $T_C = 80^{\circ}C$ 

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## Application

- Solar converter
- Uninterruptible Power Supplies

#### **Features**

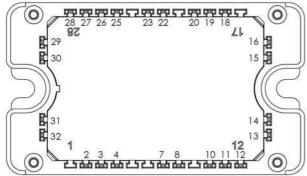
- Q2, Q3 Trench + Field Stop IGBT3
  - Low voltage drop
  - Low tail current
  - Switching frequency up to 20 kHz
  - Low leakage current
  - RBSOA and SCSOA rated

#### Q1, Q4 Super junction MOSFET

- Ultra low R<sub>DSon</sub>
- Low Miller capacitance
- Ultra low gate charge
- Avalanche energy rated
- Very rugged
- Kelvin emitter for easy drive
- Very low stray inductance
- High level of integration
- Internal thermistor for temperature monitoring

#### **Benefits**

- Stable temperature behavior
- Very rugged
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Low profile
- **RoHS** Compliant



All multiple inputs and outputs must be shorted together Example: 10/11/12; 7/8 ...

#### All ratings @ $T_i = 25^{\circ}C$ unless otherwise specified

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.



## Q1 & Q4 Absolute maximum ratings (per Super junction MOSFET)

Symbol	Parameter		Max ratings	Unit
$V_{\mathrm{DSS}}$	Drain - Source Voltage		600	V
Ţ	Continuous Drain Current	$T_c = 25^{\circ}C$	39	
$I_D$	Continuous Diani Current	$T_c = 80$ °C	29	Α
$I_{DM}$	Pulsed Drain current		160	
$V_{GS}$	Gate - Source Voltage		±20	V
$R_{DSon}$	Drain - Source ON Resistance		70	mΩ
$P_D$	Power Dissipation	$T_c = 25^{\circ}C$	250	W
$I_{AR}$	Avalanche current (repetitive and non repetitive)		20	A
E <sub>AR</sub>	Repetitive Avalanche Energy		1	I
$E_{AS}$	Single Pulse Avalanche Energy		1800	mJ

## Q1 & Q4 Electrical Characteristics (per Super junction MOSFET)

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{GS} = 0V, V_{DS} = 600V$			25	μΑ
R <sub>DS(on)</sub>	Drain – Source on Resistance	$V_{GS} = 10V, I_D = 39A$			70	$m\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 2.7 \text{mA}$	2.1	3	3.9	V
$I_{GSS}$	Gate – Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA

## Q1 & Q4 Dynamic Characteristics (per Super junction MOSFET)

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
$C_{iss}$	Input Capacitance	$V_{GS} = 0V$		7		
$C_{oss}$	Output Capacitance	$V_{\rm DS} = 25 V$		2.56		nF
$C_{rss}$	Reverse Transfer Capacitance	f = 1MHz		0.21		
$Q_{\mathrm{g}}$	Total gate Charge	$V_{GS} = 10V$		259		
$Q_{\mathrm{gs}}$	Gate – Source Charge	$V_{\text{Bus}} = 300 \text{V}$		29		nC
$Q_{\mathrm{gd}}$	Gate – Drain Charge	$I_D = 39A$		111		
$T_{d(on)}$	Turn-on Delay Time	Inductive Switching @ 125°C		21		
$T_{\rm r}$	Rise Time	$V_{GS} = 15V$		30		
T <sub>d(off)</sub>	Turn-off Delay Time	$V_{\text{Bus}} = 400V$ $I_{\text{D}} = 39A$		283		ns
$T_{\mathrm{f}}$	Fall Time	$R_G = 5\Omega$		84		
Eon	Turn-on Switching Energy	Inductive switching @ 25°C		670		т
$E_{\rm off}$	Turn-off Switching Energy	$V_{GS} = 15V, V_{Bus} = 400V$ $I_D = 39A, R_G = 5\Omega$		980		μJ
Eon	Turn-on Switching Energy	Inductive switching @ 125°C		1096		т
E <sub>off</sub>	Turn-off Switching Energy	$V_{GS} = 15V, V_{Bus} = 400V$ $I_D = 39A, R_G = 5\Omega$		1206		μJ
$R_{\text{thJC}}$	Junction to Case Thermal Resistance				0.5	°C/W



## Q2 & Q3 Absolute maximum ratings (per IGBT)

Symbol	Parameter		Max ratings	Unit
$V_{CES}$	Collector - Emitter Voltage		600	V
Ţ	Continuous Collector Current	$T_C = 25^{\circ}C$	80	
$I_{\rm C}$	Continuous Conector Current	$T_C = 80$ °C	50	A
$I_{CM}$	Pulsed Collector Current	$T_C = 25^{\circ}C$	100	
$V_{GE}$	Gate – Emitter Voltage		±20	V
$P_D$	Power Dissipation	$T_C = 25^{\circ}C$	176	W
RBSOA	Reverse Bias Safe Operating Area	$T_{\rm J} = 150^{\circ}{\rm C}$	100A @ 550V	

## Q2 & Q3 Electrical Characteristics (per IGBT)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
$I_{CES}$	Zero Gate Voltage Collector Current	$V_{GE} = 0V, V_{CE} = 600V$				250	μΑ
V	Collector Emitter Saturation Voltage	$V_{GE} = 15V$	$T_j = 25$ °C		1.5	1.9	V
$V_{CE(sat)}$	Collector Emitter Saturation Voltage	$I_C = 50A$	$T_j = 150$ °C		1.7		V
$V_{GE(th)}$	Gate Threshold Voltage	$V_{GE} = V_{CE}, I_{C} = 600 \mu A$		5.0	5.8	6.5	V
$I_{GES}$	Gate – Emitter Leakage Current	$V_{GE} = 20V, V_{CE}$	=0V			600	nA

## Q2 & Q3 Dynamic Characteristics (per IGBT)

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
Cies	Input Capacitance	$V_{GE} = 0V$		3150		
$C_{oes}$	Output Capacitance	$V_{CE} = 25V$		200		pF
$C_{res}$	Reverse Transfer Capacitance	f = 1MHz		95		
Q <sub>G</sub>	Gate charge	V <sub>GE</sub> =±15V, I <sub>C</sub> =50A V <sub>CE</sub> =300V		0.5		μС
$T_{d(on)}$	Turn-on Delay Time	Inductive Switching (25°C)		110		
$T_{r}$	Rise Time	$V_{GE} = \pm 15V$		45		
$T_{d(off)}$	Turn-off Delay Time	$V_{Bus} = 300V$ $I_{C} = 50A$		200		ns
$T_{\mathrm{f}}$	Fall Time	$R_G = 8.2\Omega$		40		
$T_{d(on)}$	Turn-on Delay Time	Inductive Switching (150°C)		120		
$T_{r}$	Rise Time	$V_{GE} = \pm 15V$		50		
$T_{d(off)}$	Turn-off Delay Time	$V_{Bus} = 300V$ $I_{C} = 50A$		250		ns
$T_{\mathrm{f}}$	Fall Time	$R_G = 8.2\Omega$		60		
Eon	Turn-on Switching Energy	$V_{GE} = \pm 15V$ $T_j = 25^{\circ}C$		0.3		mJ
Lon	Turn-on Switching Energy	$V_{Bus} = 300V$ $T_j = 150^{\circ}C$		0.43		1113
$E_{off}$	Turn-off Switching Energy	$I_C = 50A \qquad T_j = 25^{\circ}C$		1.35		mJ
2011	Take the switching Energy	$R_G = 8.2\Omega \qquad T_j = 150^{\circ}C$		1.75		1110
$I_{sc}$	Short Circuit data	$\begin{array}{l} V_{GE} \leq &15 V \; ; \; V_{Bus} = 360 V \\ t_p \leq &6 \mu s \; ; \; T_j = 150 ^{\circ} C \end{array} \label{eq:VGE}$		250		A
$R_{thJC}$	Junction to Case Thermal Resistance				0.85	°C/W



## CR2 & CR3 diode ratings and characteristics (per device)

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
$V_{F}$	Diode + tranzorb Forward Voltage	$I_F = 10A$		10		V
$R_{thJC}$	Junction to Case Thermal Resistance				8	°C/W

## CR5 & CR6 diode ratings and characteristics (per diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
$V_{RRM}$	Peak Repetitive Reverse Voltage					600	V
$I_{RM}$	Reverse Leakage Current	$V_{R} = 600V$				25	μA
$I_{\mathrm{F}}$	DC Forward Current		$Tc = 80^{\circ}C$		30		Α
		$I_F = 30A$			1.8	2.2	
$V_{\mathrm{F}}$	Diode Forward Voltage	$I_F = 60A$ $I_F = 30A$			2.2		V
			$T_j = 125$ °C		1.5		V
+	Davianca Dagayany Tima		$T_j = 25$ °C		25		***
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 30A$	$T_j = 125$ °C		160		ns
0	Reverse Recovery Charge	$V_R = 400V$ di/dt = 200A/\text{\mu}s	$T_j = 25$ °C		35		пC
$Q_{rr}$	Reverse Recovery Charge	•	$T_j = 125$ °C		480		iic
E <sub>rr</sub>	Reverse Recovery Energy	$\begin{split} I_F = 30A \\ V_R = 400V \\ di/dt = 1000A/\mu s \end{split}$	$T_j = 125$ °C		0.6		mJ
$R_{\text{thJC}}$	Junction to Case Thermal Resistance					1.2	°C/W

## CR7 & CR8 diode ratings and characteristics (per diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
$V_{RRM}$	Peak Repetitive Reverse Voltage					1200	V
$I_{RM}$	Reverse Leakage Current	$V_R = 1200V$				100	μΑ
$I_F$	DC Forward Current		$Tc = 80^{\circ}C$		30		A
		$I_F = 30A$			2.6	3.1	
$V_{\rm F}$	Diode Forward Voltage	$I_F = 60A$ $I_F = 30A$			3.2		V
	_		$T_j = 125$ °C		1.8		V
+	Davara Dagayaw Tima		$T_j = 25^{\circ}C$		300		***
$t_{rr}$	Reverse Recovery Time	$I_F = 30A$	$T_j = 125$ °C		380		ns
0	Reverse Recovery Charge	$V_R = 800V$ $di/dt = 200A/\mu s$	$T_j = 25$ °C		360		пC
$Q_{rr}$	Reverse Recovery Charge	·	$T_j = 125$ °C		1700		пС
Err	Reverse Recovery Energy	$\begin{split} I_F = 30A \\ V_R = 800V \\ di/dt = 1000A/\mu s \end{split}$	$T_j = 125$ °C		1.6		mJ
$R_{thJC}$	Junction to Case Thermal Resistance					1.2	°C/W

## Temperature sensor NTC (see application note APT0406 on www.microsemi.com for more information).

				,		
Symbol	Characteristic		Min	Typ	Max	Unit
R <sub>25</sub>	Resistance @ 25°C			50		kΩ
$\Delta R_{25}/R_{25}$				5		%
B <sub>25/85</sub>	$T_{25} = 298.15 \text{ K}$			3952		K
$\Delta \mathrm{B/B}$		$T_C=100$ °C		4		%

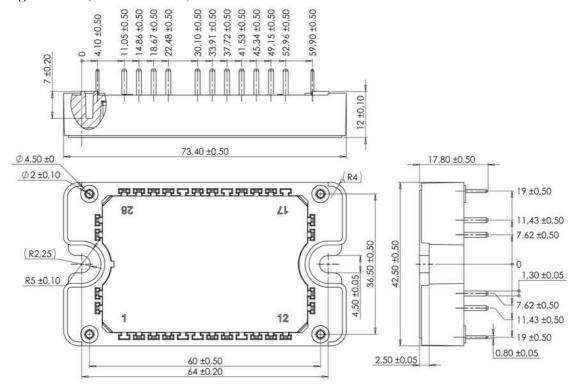
$$R_{T} = \frac{R_{25}}{\exp \left[ B_{25/85} \left( \frac{1}{T_{25}} - \frac{1}{T} \right) \right]} \quad \text{T: Thermistor temperature}$$
 
$$R_{T}: \text{ Thermistor value at T}$$

## Thermal and package characteristics

Symbol	Characteristic			Min	Max	Unit
$V_{ISOL}$	RMS Isolation Voltage, any terminal to case t = 1 min, 50/60Hz			4000		V
$T_{\rm J}$	Operating junction temperature range			-40	175*	
$T_{JOP}$	Recommended junction temperature under sv	witching condit	ions	-40	T <sub>J</sub> max -25	°C
$T_{STG}$	Storage Temperature Range			-40	125	C
$T_{\rm C}$	Operating Case Temperature			-40	125	
Torque	Mounting torque	To heatsink	M4	2	3	N.m
Wt	Package Weight				110	g

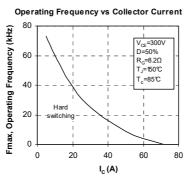
<sup>\*</sup>Tjmax = 150°C for Q1 & Q4

#### Package outline (dimensions in mm)

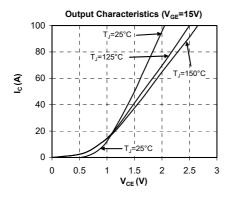


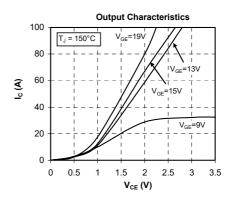
See application note 1906 - Mounting Instructions for SP3F Power Modules on www.microsemi.com

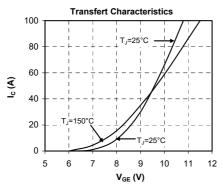
## Q2 & Q3 Typical performance curve

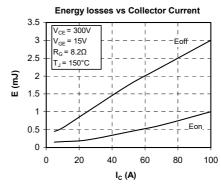


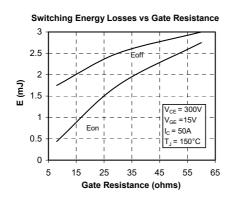


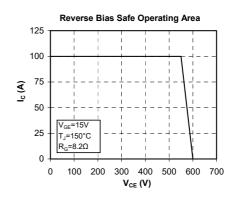


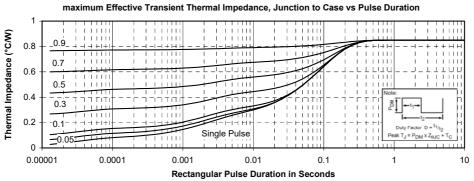






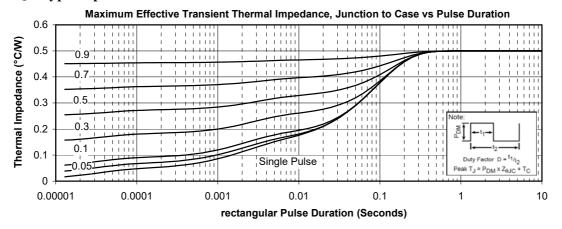


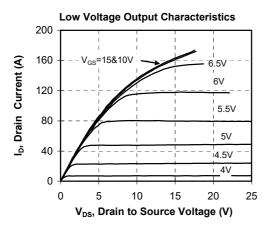


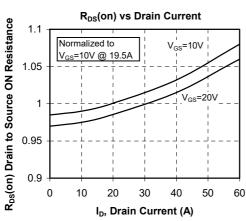


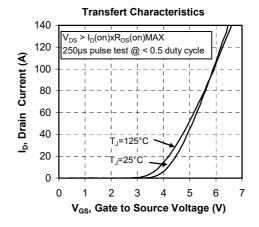


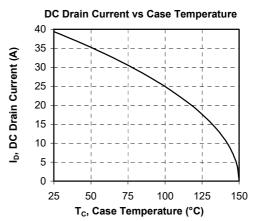
#### Q1 & Q4 Typical performance curve



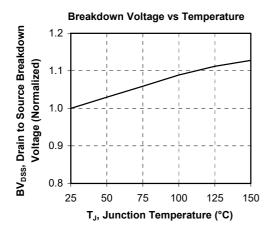


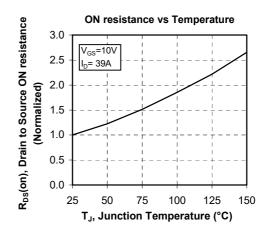


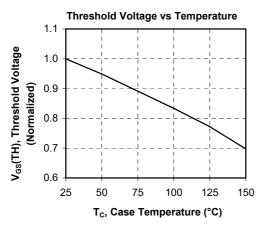


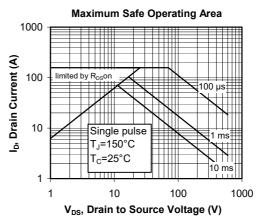


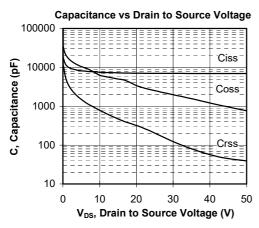


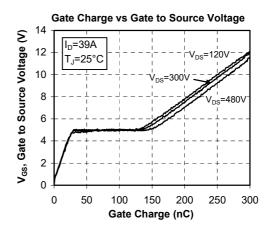




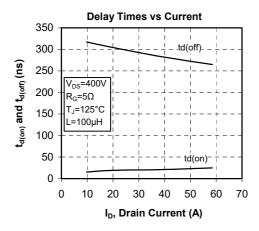


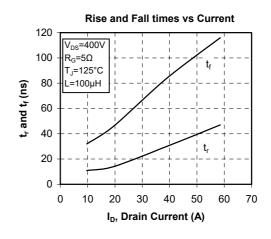


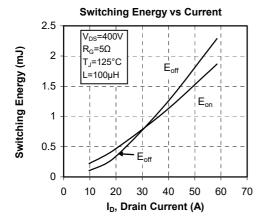


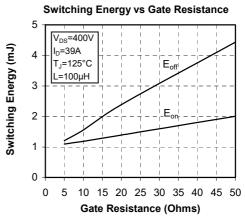


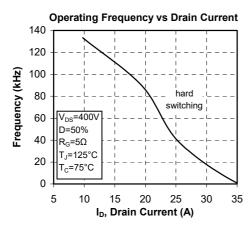


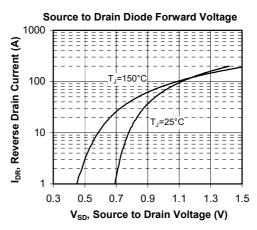






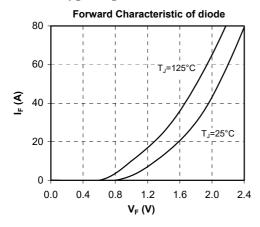


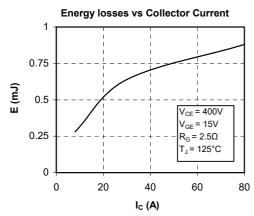


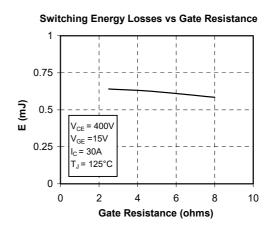


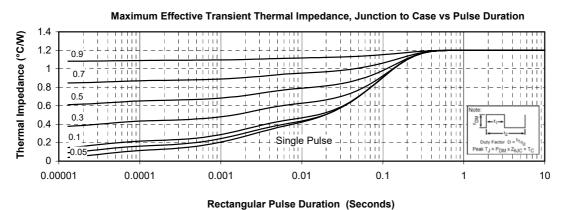


## CR5 & CR6 Typical performance curve



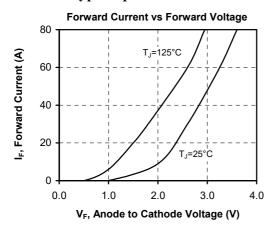




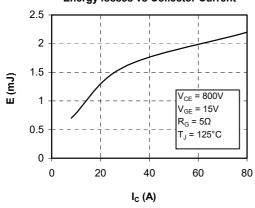




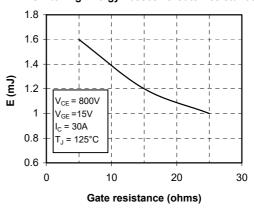
## CR7 & CR8 Typical performance curve



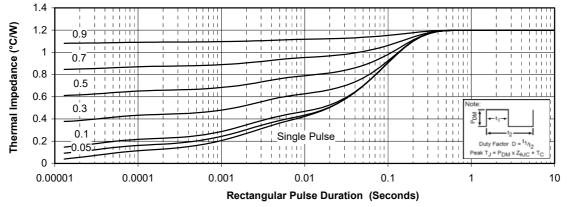
## **Energy losses vs Collector Current**



#### Switching Energy Losses vs Gate Resistance



#### Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration



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